

History of the research of Prof. Koch in the field of thin film metrology	
1988 - 1992	- Dr.-Ing. Alexander W. Koch starts research in the field of thin film metrology at the Max Planck Institute for Plasma Physics (IPP) in Garching.
1992	- Dr.-Ing. Alexander W. Koch is appointed to the Chair of the Extraordinary Professor for measurement technology at the University of Saarland and continues his research in the field of thin film metrology.
1996 - 2000	- Qilong Feng conducts his PhD research in the field of „Laser Based Interferometric Remote Measuring Technique for the Determination of Film Thicknesses and Film Properties“.
1998	- Prof. Dr.-Ing. Alexander W. Koch is appointed to the Chair of the Institute for Measurement Systems and Sensor Technology (MST) at the Technische Universität München (TUM) and continues his research in the field of thin film metrology.
2007 - 2010	- Research project "Optical Measurement Technology" in the joint project "Basis for the next generation X of printed electronics through networked development of materials, component analysis, and printing processes - MaDriX" funded by the Federal Ministry of Education and Research (BMBF). - Florian Hirth conducts his PhD research in the field of „Film Thickness Measurements on Printed Polymer Layer Systems“.
2013 - 2017	- Research project "Hyperspectral Chromatical Reflectometer for Measuring of Moving Objects" funded by the German Research Foundation (DFG). - Anton Tremmel conducts his PhD research.
2017 - 2021	- Xingchen Dong conducts his PhD research in the field of „Hyperspectral Imaging“.

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